
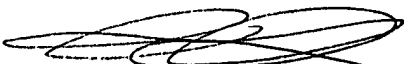



Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/661,223	KAIBUKI, FUTOSHI	
	Examiner	Art Unit	
	Kim T. Huynh	2112	

ISSUE CLASSIFICATION									
ORIGINAL				CROSS REFERENCE(S)					
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
710		305		710	306				
INTERNATIONAL CLASSIFICATION									
G	0	6	F	13/14					
				/					
				/					
				/					
				/					
<u>wt</u> Kim T. Huynh 1/10/06 (Assistant Examiner) (Date)				 REHANA PERVEEN SUPERVISORY PATENT EXAMINER (P Primary Examiner) (Date) <u>1/10/06</u>			Total Claims Allowed: 14		
 <u>1/11/06</u> (Legal Instruments Examiner) (Date)							O.G. Print Claim(s) 1		O.G. Print Fig. 1

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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